


<b>Search Notes</b>  	<b>Application/Control No.</b>  10580713	<b>Applicant(s)/Patent Under Reexamination</b>  MARUYAMA ET AL.
	<b>Examiner</b>  BENJAMIN P LEE	<b>Art Unit</b>  3641

SEARCHED			
Class	Subclass	Date	Examiner
102	202.7	12/18/2008	LEE
102	202.9	12/18/2008	LEE
102	202.14	12/18/2008	LEE
102	205	12/18/2008	LEE
102	367	12/18/2008	LEE
102	368	12/18/2008	LEE
102	369	12/18/2008	LEE
102	370	12/18/2008	LEE
102	334	12/18/2008	LEE

SEARCH NOTES		
Search Notes	Date	Examiner
Text search	12/18/2008	LEE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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